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Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/660,063	BEYNON ET AL.	
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SEARCHED				
Class	Subclass	Date	Examiner ·	
. 709	204-207	2/12/2007	JN	
704	270-278	2/12/2007	JN	
704	231-257	2/12/2007	. JN	
707	9 .	2/12/2007	JN	
715	768	2/12/2007	JN	
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INTERFERENCE SEARCHED				
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SEARCH NOT (INCLUDING SEARCH		)
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East: USPAT, US PGPUB, EPO, JPO, Derwent, IBM-IDB	2/12/2007	JN
NPL	2/12/2007	JN∵
Consulted with primary examiner, Ba Huynh, AU 2179	2/12/2007	.JN
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